

ABSTRACT OF THE DISCLOSURE

An IC testing apparatus which overcomes the shortcoming of the prior art by permitting a recognition of the attitude of an IC being measured in a proper manner to each variety of IC's in a simple and facilitated manner is disclosed. IC testing apparatus includes a handler on which an IC socket 2 and a socket guide 3 which is centrally formed with a square opening 30 into which the IC socket 2 is fitted are mounted. A projected light guide having a light radiating end on which a light reflecting surface r is formed is embedded in the socket guide 3. A received light guide having a light incident end on which a light reflecting surface is formed is also embedded in the socket guide 3 in parallel relationship with the projected light guide. A light projector element is disposed in opposing relationship with the projected light guide, and a light receptor element is disposed in opposing relationship with the received light guide.

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